

<b>Notice of References Cited</b>	Application/Control No. 10/810,819		Applicant(s)/Patent Under Reexamination BRUGEMANN ET AL.	
	Examiner Allen C. Ho		Art Unit 2882	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,859,520 B2	02-2005	He et al.	378/79
*	B	US-2005/0002487 A1	01-2005	Blomsma et al.	378/075
*	C	US-6,836,532 B2	12-2004	Durst et al.	378/73
*	D	US-2004/0258203 A1	12-2004	Yamano et al.	378/073
*	E	US-6,718,008 B1	04-2004	He et al.	378/71
*	F	US-6,697,454 B1	02-2004	Nicolich et al.	378/85
*	G	US-6,577,705 B1	06-2003	Chang et al.	378/45
*	H	US-6,507,636 B1	01-2003	Lehmann, Christian W.	378/79
*	I	US-6,459,763 B1	10-2002	Koinuma et al.	378/71
*	J	US-6,404,849 B1	06-2002	Olson et al.	378/79
*	K	US-2002/0067800 A1	06-2002	Newman et al.	378/73
*	L	US-6,371,640 B1	04-2002	Hajduk et al.	378/208
*	M	US-3,564,240	02-1971	Thomas, Jr., Roy Leander	378/81

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity, Elements of X-RAY DIFFRACTION, second edition, p. 155-156, Addison-Wesley, Reading, MA, 1978.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.